

UTC UNISONIC TECHNOLOGIES CO., LTD

16N50 **Preliminary Power MOSFET**

16 Amps, 500 Volts **N-CHANNEL POWER MOSFET**

DESCRIPTION

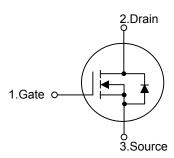
The UTC 16N50 is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

The UTC 16N50 is generally applied in high efficiency switch mode power supplies, active power factor correction and electronic lamp ballasts based on half bridge topology.



- * 16A, 500V, $R_{DS(ON)}$ =0.38 Ω @ V_{GS} =10V
- * High Switching Speed
- * 100% Avalanche Tested

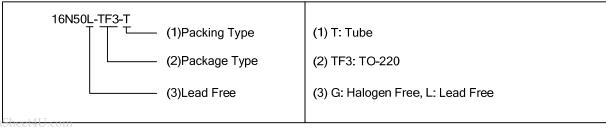




ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
16N50L-TF3-T	16N50G-TF3-T	TO-220F	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



TO-220F

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■ **ABSOLUTE MAXIMUM RATINGS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	500	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	Continuous (T _C =25°C)	I _D	16 (Note 2)	Α
	Pulsed (Note 3)	I _{DM}	64 (Note 2)	Α
Avalanche Current (Note 3)		I _{AR}	16	Α
Avalanche Energy	Single Pulsed (Note 4)	E _{AS}	780	mJ
	Repetitive (Note 5)	E _{AR}	20	mJ
Peak Diode Recovery dv/dt (Note 5)		dv/dt	4.5	V/ns
Power Dissipation	T _C =25°C	ר	52	W
	Derate above 25°C	- P _D	0.41	W/°C
Junction Temperature		TJ	+150	°C
Storage Temperature		T _{STG}	-55~+150	°C

Note: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Drain current limited by maximum junction temperature
- 3. Repetitive Rating: Pulse width limited by maximum junction temperature
- 4. L = 5.5mH, I_{AS} = 16A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 5. $I_{SD} \le 16A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	62.5	°C/W
Junction to Case	θ_{JC}	2.4	°C/W

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■ ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

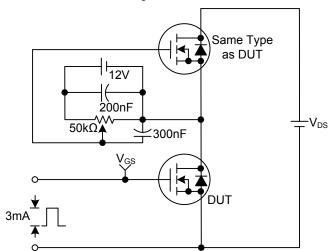
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	I _D =250μA, V _{GS} =0V				V
Drain-Source Leakage Current		I _{DSS}	V _{DS} =500V, V _{GS} =0V			1	μΑ
Gate- Source Leakage Current	Forward		V_{GS} =+30V, V_{DS} =0V			+100	nΑ
	Reverse	I_{GSS}	V_{GS} =-30V, V_{DS} =0V			-100	nA
ON CHARACTERISTICS	ON CHARACTERISTICS						
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_{D}=250\mu A$ 2.0			4.0	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =8A		0.31	0.38	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C _{ISS}			1495	1945	pF
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		235	310	pF
Reverse Transfer Capacitance		C_{RSS}			20	30	pF
SWITCHING PARAMETERS							
Total Gate Charge		Q_G	\/ -40\/ \/ -400\/ -46A		32	45	nC
Gate to Source Charge		Q_GS	V _{GS} =10V, V _{DS} =400V, I _D =16A (Note 6, 7)		8.5		nC
Gate to Drain Charge		Q_GD			14		nC
Turn-ON Delay Time		$t_{D(ON)}$	V _{DD} =250V, I _D =16A, R _G =25Ω (Note 6, 7)		40	90	ns
Rise Time		t_R			150	310	ns
Turn-OFF Delay Time		t _{D(OFF)}			65	140	ns
Fall-Time		t_{F}			80	170	ns
SOURCE- DRAIN DIODE RATIN	NGS AND (CHARACTERI	STICS				
Maximum Body-Diode Continuous Current		Is				9.2	Α
Maximum Body-Diode Pulsed Current		I _{SM}				37	Α
Drain-Source Diode Forward Voltage		V_{SD}	I _S =16A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time		t _{RR}	I _S =16A, V _{GS} =0V, dI _F /dt=100A/μs (Note 6)		490		ns
Body Diode Reverse Recovery Charge		Q_{RR}			5.0		μC

Notes: 6. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%

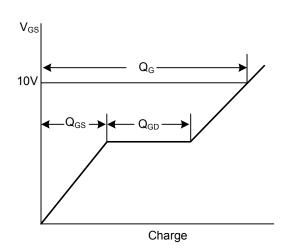
^{7.} Essentially independent of operating temperature

■ TEST CIRCUITS AND WAVEFORMS

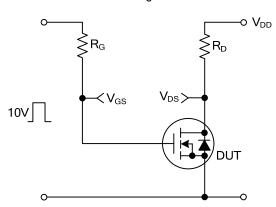
Gate Charge Test Circuit



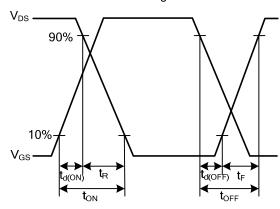
Gate Charge Waveforms



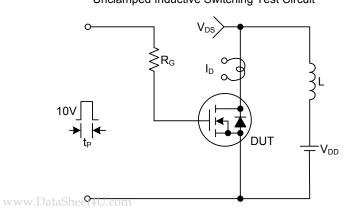
Resistive Switching Test Circuit



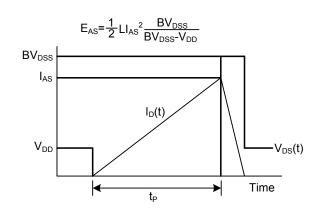
Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit

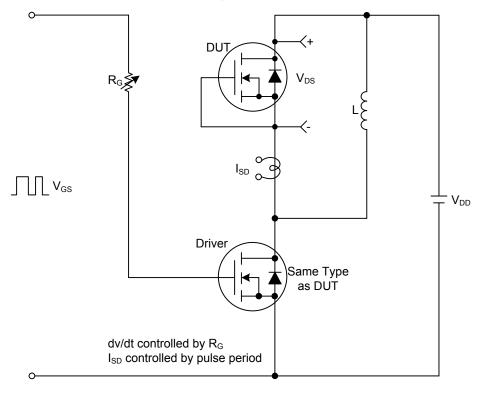


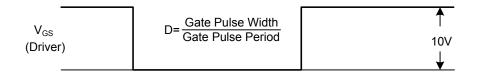
Unclamped Inductive Switching Waveforms

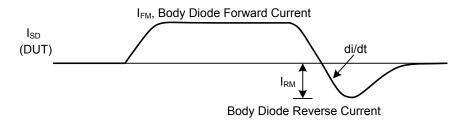


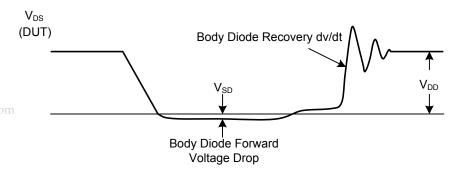
■ TEST CIRCUITS AND WAVEFORMS(Cont.)











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